

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S2	1778	"324"/\$.ccls. and wafer and semiconductor	USPAT	OR	OFF	2001/10/10 10:09
S3	450	"324"/\$.ccls. and wafer and semiconductor and probe adj card	USPAT	OR	OFF	2001/10/10 10:10
S5	412	324/7\$2.ccls. and wafer and semiconductor and probe adj card and test	USPAT	OR	OFF	2001/10/10 10:12
S7	137	324/7\$2.ccls. and wafer and semiconductor and probe adj card and test and alignment and needle	USPAT	OR	ON	2001/10/10 10:19
S8	60	324/7\$2.ccls. and wafer and semiconductor adj device and probe adj card and test and alignment and needle	USPAT	OR	ON	2001/10/10 10:26
S10	132	324/754.ccls. and wafer and semiconductor adj device and probe adj card and test	USPAT	OR	ON	2001/10/10 10:44
S12	86	324/75\$1.ccls. and wafer and semiconductor adj device and probe adj card and test and needle	USPAT	OR	ON	2001/10/10 10:46
S11	62	324/754.ccls. and wafer and semiconductor adj device and probe adj card and test and needle	USPAT	OR	ON	2001/10/10 10:50
S13	132	324/754.ccls. and wafer and semiconductor adj device and probe adj card and test	USPAT	OR	ON	2001/10/10 10:56
S14	57	324/765.ccls. and wafer and semiconductor adj device and probe adj card and test	USPAT	OR	ON	2001/10/10 10:57
S15	186	324/765.ccls. and wafer and semiconductor adj device and probe	USPAT	OR	ON	2001/10/10 10:58
S17	3	324/765.ccls. and rost\$.inv. and probe	USPAT	OR	OFF	2001/10/10 11:03
S16	3	324/765.ccls. and rost\$.inv.	USPAT	OR	OFF	2001/10/10 11:03
S19	3	324/765.ccls. and Rostoker\$.inv. and probe	USPAT	OR	OFF	2001/10/10 11:05
S18	3	324/765.ccls. and rost\$.inv. and probe	USPAT	OR	OFF	2001/10/10 11:05
S21	5	324/765.ccls. and Rostoker and probe adj card	USPAT	OR	OFF	2001/10/10 11:06
S20	25	324/765.ccls. and Rostoker and probe	USPAT	OR	OFF	2001/10/10 11:06
S9	224	324/7\$2.ccls. and wafer and semiconductor adj device and probe adj card and test	USPAT	OR	ON	2001/10/10 12:05

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S6	176	324/7\$2.ccls. and wafer and semiconductor and probe adj card and test and needles	USPAT	OR	OFF	2001/10/10 12:06
S24	1	("6400173").PN.	USPAT; USOCR	OR	OFF	2003/03/26 10:41
S23	1	("20020171449").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2003/03/26 10:41
S22	228	324/7\$2.ccls. and wafer and semiconductor and probe adj card and test and needles	USPAT	OR	ON	2003/03/26 10:59
S25	78	wafer and semiconductor and test with program and simulat\$3 and emulat\$3	USPAT	OR	ON	2003/03/26 11:01
S26	120	wafer and semiconductor and test with program and emulat\$3	USPAT	OR	ON	2003/03/26 11:02
S27	56	semiconductor and test with program and emulat\$3 with simulat\$3	USPAT	OR	ON	2003/03/26 11:10
S28	753	"714"/\$.ccls. and semiconductor and test with program	USPAT	OR	ON	2003/03/26 11:12
S31	71	"714"/\$.ccls. and semiconductor with chip and test with program and probe	USPAT	OR	ON	2003/03/26 11:13
S30	12	"714"/\$.ccls. and semiconductor with wafer with chip and test with program and probe	USPAT	OR	ON	2003/03/26 11:13
S29	7	"714"/\$.ccls. and semiconductor with chip and test with program and probe with card	USPAT	OR	ON	2003/03/26 11:13
S1	1	("5656943").PN.	USPAT; USOCR	OR	OFF	2003/12/11 11:39
S35	76	"5070297".URPN.	USPAT	OR	OFF	2003/12/11 11:40
S34	6	("4038599" "4520314" "4799009" "4928278" "4961052" "4965865").PN.	USPAT	OR	OFF	2003/12/11 11:40
S33	1	("5070297").PN.	USPAT; USOCR	OR	OFF	2003/12/11 11:42
S36	1	("6400173").PN.	USPAT; USOCR	OR	OFF	2003/12/11 11:43
S32	65	"5070297"	USPAT	OR	OFF	2006/02/22 09:28
S45	1	"20040175850"	US-PGPUB; USPAT	OR	OFF	2006/02/22 10:07
S44	1	("6727723").PN.	USPAT	OR	OFF	2006/02/22 10:07
S46	1	("5070297").PN.	USPAT	OR	OFF	2006/02/22 11:43

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S47	109	"324"/\$.ccls. and plurality near wafer and semiconductor and probe adj card and test	USPAT	OR	OFF	2006/02/22 11:47
S4	425	"324"/\$.ccls. and wafer and semiconductor and probe adj card and test	USPAT	OR	OFF	2006/02/22 11:47
S49	24	"324"/\$.ccls. and plurality near wafer with probe adj card and test	USPAT	OR	ON	2006/02/22 11:48
S48	132	"324"/\$.ccls. and plurality near wafer and semiconductor and probe adj card and test	USPAT	OR	ON	2006/02/22 11:48
S51	1	"324"/\$.ccls. and plurality near wafers with probe adj card with test\$3	USPAT	OR	OFF	2006/02/22 11:49
S50	18	"324"/\$.ccls. and plurality near wafer with probe adj card with test\$3	USPAT	OR	ON	2006/02/22 11:49
S52	152	"324"/\$.ccls. and wafers with probe adj card with test\$3	USPAT	OR	OFF	2006/02/22 11:50
S53	63	"324"/\$.ccls. and wafers near test\$3 with probe adj card	USPAT	OR	OFF	2006/02/22 11:55
S57	7	"324"/\$.ccls. and plurality adj wafer with test\$3 with probe adj card	USPAT	OR	ON	2006/02/22 11:57
S58	10	"324"/\$.ccls. and plurality adj wafer with probe adj card	USPAT	OR	ON	2006/02/22 11:58
S60	5	"324"/\$.ccls. and plurality adj wafers same probe adj card	USPAT	OR	OFF	2006/02/22 11:59
S59	1	"324"/\$.ccls. and plurality adj wafers with probe adj card	USPAT	OR	OFF	2006/02/22 11:59